

Supporting information for

A Facile One-step Method to Reduce Surface Impurities in Solution-Processed CuInS_2 Nanocrystals Solar Cell

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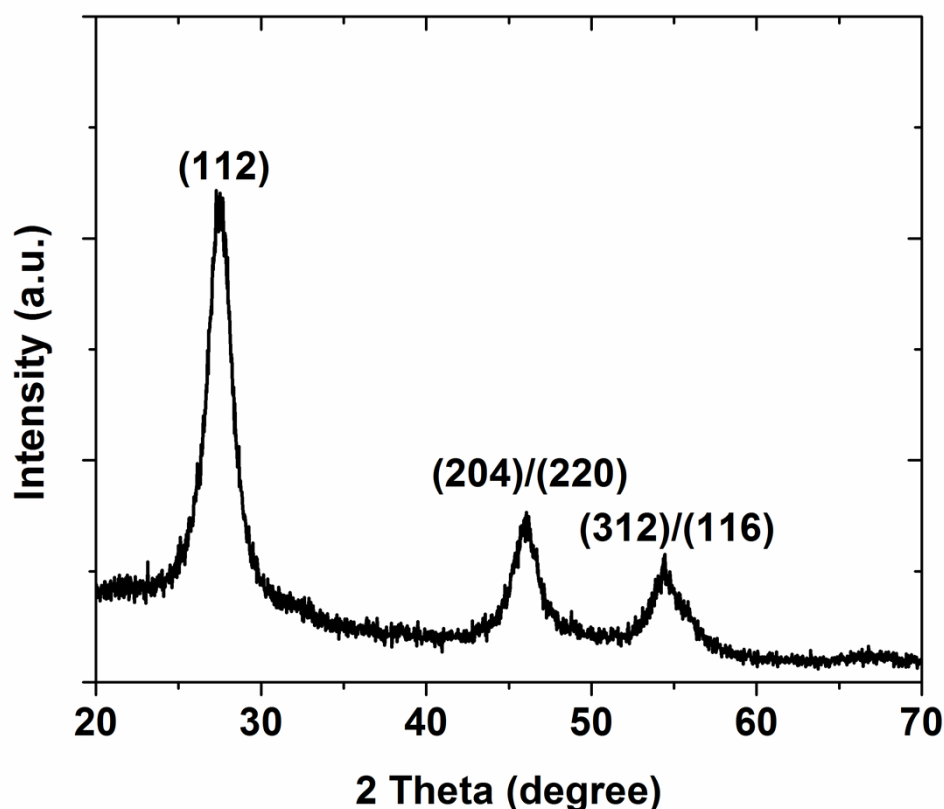


Figure S1: Grazing incidence X-ray diffraction pattern of CIS NCs thin film.

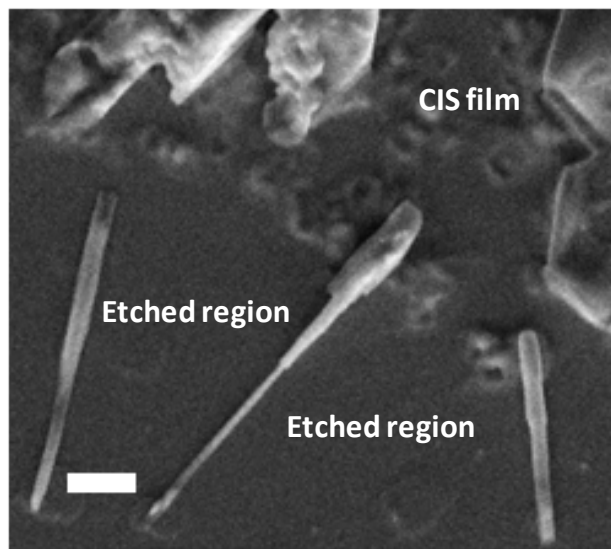


Figure S2. SEM top-view images (scale bar: 10 μm) of CuInS_2 film after the solvent treatment with DMSO. DMSO washing resulted in an extensive film etching.

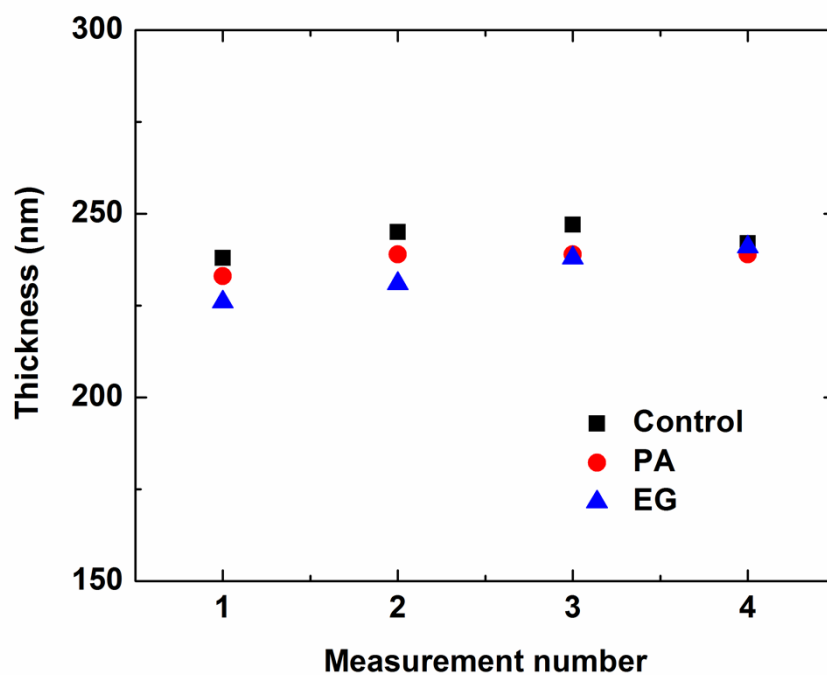


Figure S3. Thickness variations of the CIS absorber film before and after the solvent washing with propionic acid (PA) and Ethylene glycol (EG). Thickness remains fairly constant with the solvent washing. The graph shows four different thickness measurements for each sample to show the error in the measurement.